

**Search Notes**

Application/Control No.

10/848,932

Examiner

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Applicant(s)/Patent under  
Reexamination

LIEW, JOSEPH SHU YIAN

Art Unit

3679

**SEARCHED**

Class	Subclass	Date	Examiner
285	322	1/12/2006	DB
	323		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR